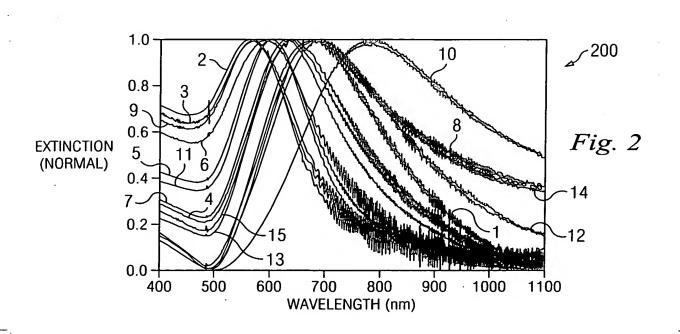
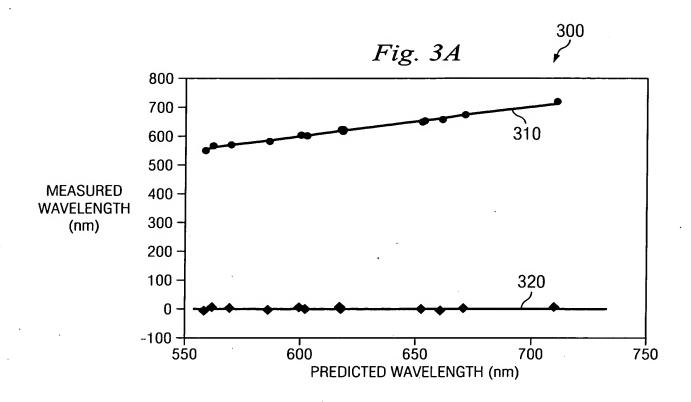
1/8

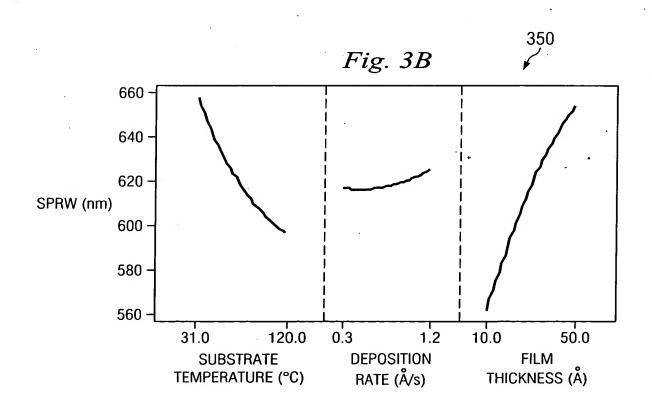
SAMPLE	SUBSTRATE TEMPERATURE (°C)	DEPOSITION RATE (Å/s)	FILM THICKNESS (Å)	SPRW (nm)
1	31	0.3	30	649
2	· 120	0.3	30	601
3	31	1.2	30	671
4	75.5	0.75	30	615
5	75.5	1.2	50	654
6	75.5	0.75	30	623
7	120	0.75	50∙	620
8	31	0.75	50	716
9	75.5	1,2	10	572
10	75.5	0.75	30	614
11	120	0.75	· 10	552
12	75.5	0.3	50	650
13	75.5	0.3	10	658
14	120	1.2	30	602
15	31	0.75	10 ·	582

J 100

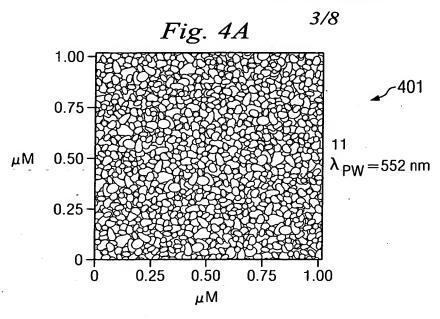
Fig. 1

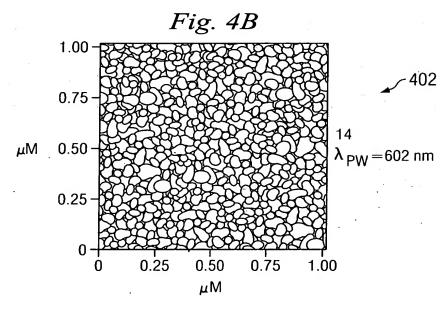


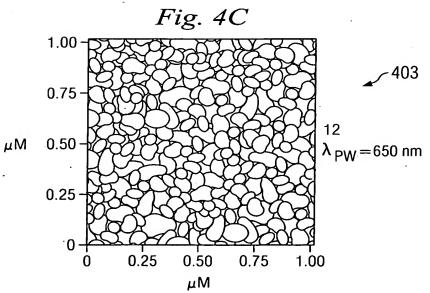


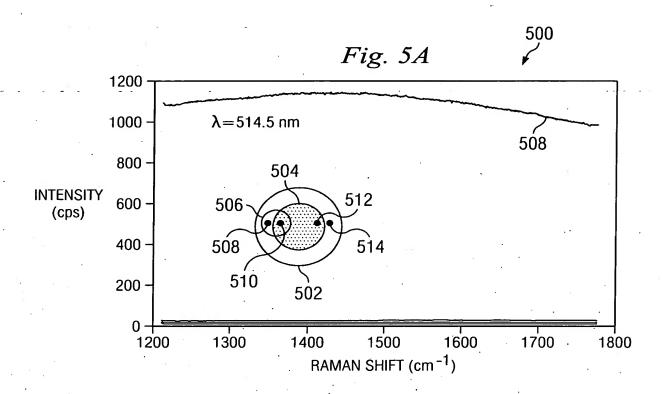


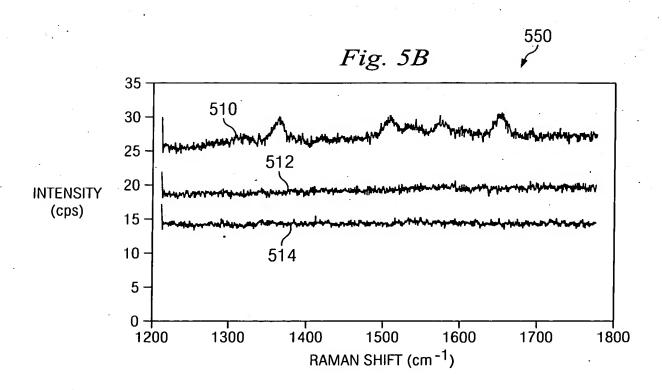
Attorney Docket No. 34003.31 Applicant: Wayne A. Weimer Serial No.: N/A Filed: Herewith Title: Systems and Method for Detection of Low Concentration Of Molecules











Attorney Docket No. 34003.31 Applicant: Wayn A. Weimer Serial No.: N/A Filed: Herewith Title: Systems and Method for Detection of Low Concentration Of Molecules

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